

# TRENCH Gen5 TMOS

# DIM3600ESM17-PT500

# **Single Switch IGBT Module**

Replaces DS6328-3

DS6328-4 October 2024 (LN43694)

## **FEATURES**

- Trench Gate IGBT
- 10µs Short Circuit Withstand
- High Thermal Cycling Capability
- Low V<sub>ce(sat)</sub> Device
- High Current Density
- Isolated AISiC Base with AIN Substrates

## **APPLICATIONS**

- High Reliability Inverters
- Motor Controllers
- Smart Grid
- Traction Drives

The Powerline range of high power modules includes half bridge, chopper, dual, single and bi-directional switch configurations covering voltages from 1200V to 6500V and currents up to 3600A.

The DIM3600ESM17-PT500 is a single switch 1700V, trench gate, insulated gate bipolar transistor (IGBT) module with enhanced field stop and implantation technology. The IGBT has a wide reverse bias safe operating area (RBSOA) plus 10µs short circuit withstand. This device is optimised for traction drives and other applications requiring high thermal cycling capability.

The module incorporates an electrically isolated base plate and low inductance construction enabling circuit designers to optimise circuit layouts and utilise grounded heat sinks for safety.

## ORDERING INFORMATION

Order As:

## DIM3600ESM17-PT500

Note: When ordering, please use the complete part number

## **KEY PARAMETERS**

V <sub>CES</sub>		1700V
V <sub>CE(sat)</sub>	* (typ)	1.95V
Ic	(max)	3600A
I <sub>C(PK)</sub>	(max)	7200A

\* Measured at the the auxiliary terminals

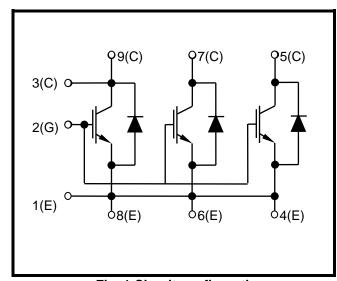


Fig. 1 Circuit configuration

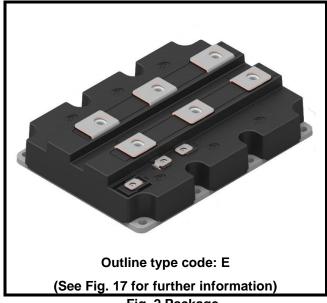


Fig. 2 Package

## **ABSOLUTE MAXIMUM RATINGS**

Stresses above those listed under 'Absolute Maximum Ratings' may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed. Exposure to Absolute Maximum Ratings may affect device reliability.

T<sub>case</sub> = 25°C unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
Vces	Collector-emitter voltage	V <sub>GE</sub> = 0V	1700	V
V <sub>GES</sub>	Gate-emitter voltage		±20	V
Ic	Continuous collector current	T <sub>case</sub> = 95°C, T <sub>vj</sub> max = 175°C	3600	Α
I <sub>C(PK)</sub>	Peak collector current	1ms,	7200	Α
P <sub>max</sub>	Max. transistor power dissipation	$T_{case} = 25^{\circ}C, T_{vj} = 175^{\circ}C$	20	kW
l²t	Diode I <sup>2</sup> t value	$V_R = 0$ , $t_p = 10$ ms, $T_{vj} = 150$ °C	2200	kA <sup>2</sup> s
Visol	Isolation voltage – per module	Commoned terminals to base plate. AC RMS, 1 min, 50Hz	5000	V
PDEV	Extinction voltage – per module	After 1 minute of V <sub>isol</sub>	≥2600	V

## THERMAL AND MECHANICAL RATINGS

Internal insulation material:

Baseplate material:

Creepage distance:

Clearance:

CTI (Comparative Tracking Index):

AIN

AISiC

33mm

20mm

>600

Symbol	Parameter	Test Conditions	Min	Тур.	Max	Units
R <sub>th(j-c)</sub>	Thermal resistance – IGBT	Continuous dissipation - junction to case			7.5	°C/kW
R <sub>th(j-c)</sub>	Thermal resistance – diode	Continuous dissipation - junction to case			9.5	°C/kW
R <sub>th(c-h)</sub>	Thermal resistance – case to heatsink (IGBT)	Mounting torque 5Nm (with mounting grease)		9.7		°C/kW
R <sub>th(c-h)</sub>	Thermal resistance – case to heatsink (diode)	Mounting torque 5Nm (with mounting grease)		10.5		°C/kW
т.	Junction temperature	Transistor	-40		150	°C
Tj		Diode	-40		150	°C
T <sub>stg</sub>	Storage temperature range	-	-40		150	°C
		Mounting – M6			5	Nm
	Screw torque	Electrical connections – M4			2	Nm
		Electrical connections – M8			10	Nm

# **ELECTRICAL CHARACTERISTICS**

 $T_{case}$  = 25°C unless stated otherwise.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Ices	Collector cut-off current	V <sub>GE</sub> = 0V, V <sub>CE</sub> = V <sub>CES</sub>			1	mA
		V <sub>GE</sub> = 0V, V <sub>CE</sub> = V <sub>CES</sub> , T <sub>case</sub> = 125°C			60	mA
		V <sub>GE</sub> = 0V, V <sub>CE</sub> = V <sub>CES</sub> , T <sub>case</sub> = 150°C			100	mA
I <sub>GES</sub>	Gate leakage current	V <sub>GE</sub> = ± 20V, V <sub>CE</sub> = 0V			1	μA
V <sub>GE(TH)</sub>	Gate threshold voltage	Ic = 120mA, V <sub>GE</sub> = V <sub>CE</sub>	5.5	6.1	6.7	V
		V <sub>GE</sub> = 15V, I <sub>C</sub> = 3600A		1.95	2.35	V
V <sub>CE(sat)</sub>	Collector-emitter saturation voltage	V <sub>GE</sub> = 15V, I <sub>C</sub> = 3600A, T <sub>j</sub> = 125°C		2.20		V
	- Canada and a canada	V <sub>GE</sub> = 15V, I <sub>C</sub> = 3600A, T <sub>j</sub> = 150°C		2.25		V
lF	Diode forward current	DC		3600		Α
I <sub>FM</sub>	Diode maximum forward current	$t_p = 1 ms$		7200		Α
	Diode forward voltage	IF = 3600A		1.80		V
$V_{F}$		I <sub>F</sub> = 3600A, T <sub>j</sub> = 125°C		1.85		V
		I <sub>F</sub> = 3600A, T <sub>j</sub> = 150°C		1.85		V
Cies	Input capacitance	V <sub>CE</sub> = 25V, V <sub>GE</sub> = 0V, f = 100kHz		601		nF
Qg	Gate charge	±15V		37.8		μC
Cres	Reverse transfer capacitance	V <sub>CE</sub> = 25V, V <sub>GE</sub> = 0V, f = 100kHz		0.4		nF
L <sub>M</sub>	Module inductance			6		nΗ
RINT	Internal transistor resistance			85		μΩ
SC <sub>Data</sub>	Short circuit current, Isc	$T_{j} = 150^{\circ}C$ , $V_{CC} = 1000V$ $t_{p} \le 10\mu s$ , $V_{GE} \le 15V$ $V_{CE (max)} = V_{CES} - L^{*} x di/dt$ IEC 60747-9		14400		А

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Note:  $^{\star}$  L is the circuit inductance +  $L_{\text{M}}$ 

# **ELECTRICAL CHARACTERISTICS**

 $T_{case} = 25$ °C unless stated otherwise

Symbol	Parameter	Test Conditions	Min	Тур.	Max	Units
$t_{d(off)}$	Turn-off delay time	Ic = 3600A		2175		ns
t <sub>f</sub>	Fall time	$V_{GE} = \pm 15V$		245		ns
Eoff	Turn-off energy loss	V <sub>CE</sub> = 900V		1585		mJ
t <sub>d(on)</sub>	Turn-on delay time	$R_{G(ON)} = 0.5\Omega$ $R_{G(OFF)} = 0.5\Omega$ $L_{S} \sim 60 \text{nH}$		970		ns
t <sub>r</sub>	Rise time			310		ns
E <sub>ON</sub>	Turn-on energy loss			370		mJ
Qrr	Diode reverse recovery charge	I <sub>F</sub> = 3600A		845		μC
Irr	Diode reverse recovery current	V <sub>CE</sub> = 900V dI <sub>F</sub> /dt = 11000A/μs		1960		Α
Erec	Diode reverse recovery energy			650		mJ

# T<sub>case</sub> = 125°C unless stated otherwise

Symbol	Parameter	Test Conditions	Min	Тур.	Max	Units
t <sub>d(off)</sub>	Turn-off delay time	Ic = 3600A		2280		ns
t <sub>f</sub>	Fall time	$V_{GE} = \pm 15V$		300		ns
E <sub>OFF</sub>	Turn-off energy loss	V <sub>CE</sub> = 900V		1760		mJ
t <sub>d(on)</sub>	Turn-on delay time	$R_{G(ON)} = 0.5\Omega$ $R_{G(OFF)} = 0.5\Omega$ $L_{S} \sim 60 \text{nH}$		970		ns
t <sub>r</sub>	Rise time			320		ns
Eon	Turn-on energy loss			600		mJ
Qrr	Diode reverse recovery charge	I <sub>F</sub> = 3600A		1410		μC
Irr	Diode reverse recovery current	V <sub>CE</sub> = 900V dI <sub>F</sub> /dt = 11000A/μs		2390		Α
E <sub>rec</sub>	Diode reverse recovery energy			1120		mJ

# T<sub>case</sub> = 150°C unless stated otherwise

Symbol	Parameter	Test Conditions	Min	Тур.	Max	Units
t <sub>d(off)</sub>	Turn-off delay time	Ic = 3600A		2310		ns
t <sub>f</sub>	Fall time	$V_{GE} = \pm 15V$		315		ns
E <sub>OFF</sub>	Turn-off energy loss	V <sub>CE</sub> = 900V		1790		mJ
t <sub>d(on)</sub>	Turn-on delay time	$R_{G(ON)} = 0.5\Omega$		970		ns
t <sub>r</sub>	Rise time	$R_{G(OFF)} = 0.5\Omega$		330		ns
Eon	Turn-on energy loss	Ls ~ 60nH		650		mJ
Qrr	Diode reverse recovery charge	I <sub>F</sub> = 3600A		1660		μC
Irr	Diode reverse recovery current	V <sub>CE</sub> = 900V dI <sub>F</sub> /dt = 11000A/µs		2550		Α
Erec	Diode reverse recovery energy			1240		mJ

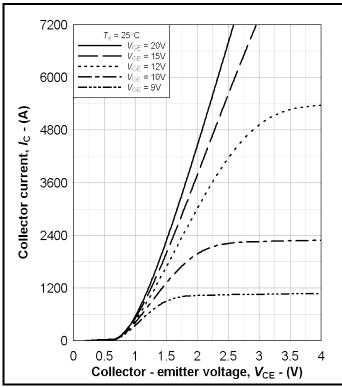


Fig. 3 Typical IGBT output characteristics

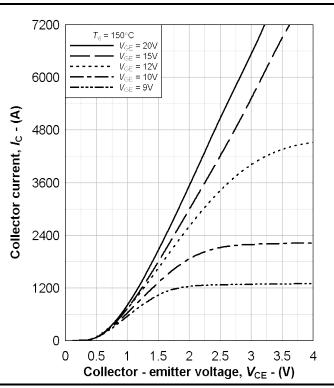


Fig. 4 Typical IGBT output characteristics

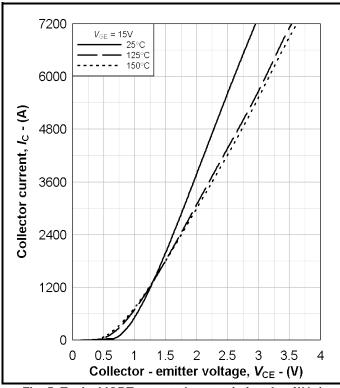


Fig. 5 Typical IGBT output characteristics,  $I_C = f(V_{CE})$ 

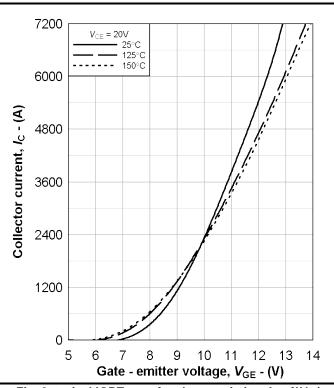


Fig. 6 typical IGBT transfer characteristics,  $I_C = f(V_{GE})$ 

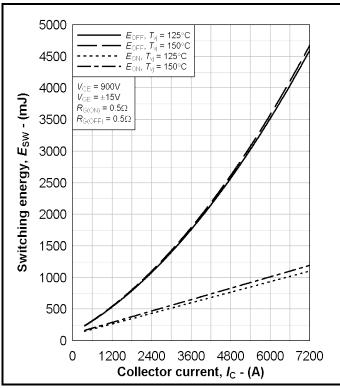


Fig. 7 Typical IGBT switching energy,  $E_{ON} = f(I_C), E_{OFF} = f(I_C)$ 

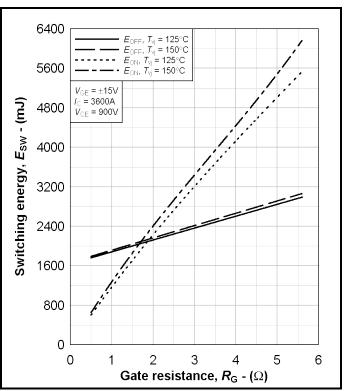


Fig. 8 Typical IGBT switching energy  $E_{ON} = f(R_G)$ ,  $E_{OFF} = fR_G$ )

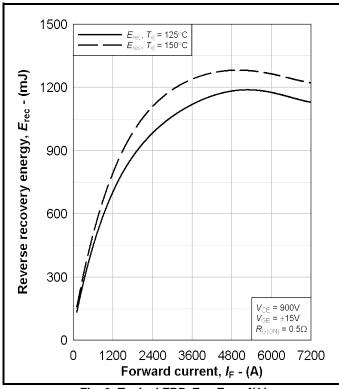


Fig. 9 Typical FRD  $E_{rec}$ ,  $E_{rec} = f(I_F)$ 

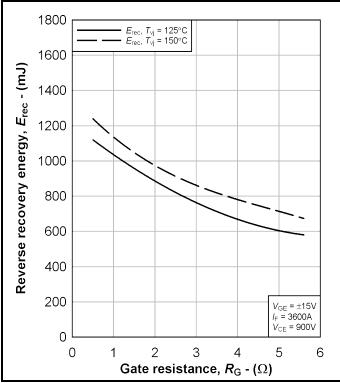


Fig. 10 Typical FRD  $E_{rec}$ ,  $E_{rec} = f(R_G)$ 

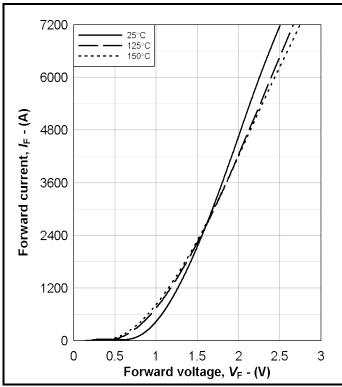


Fig. 11 Typical FRD output characteristics,  $I_F = f(V_F)$ 

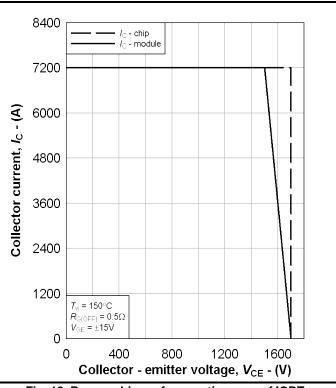


Fig. 12 Reverse bias safe operating area of IGBT,  $I_C = f(V_{CE})$ 

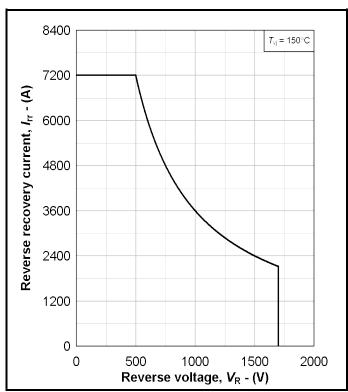


Fig. 13 Diode reverse bias safe operating area

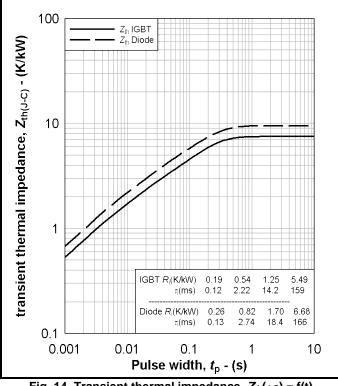


Fig. 14 Transient thermal impedance,  $Z_{th}(J-C) = f(t)$ 

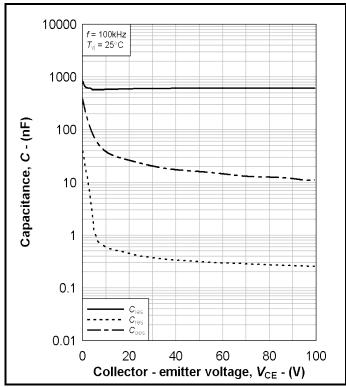


Fig. 15 Typical capacitor characteristic, C = f (V<sub>CE</sub>)

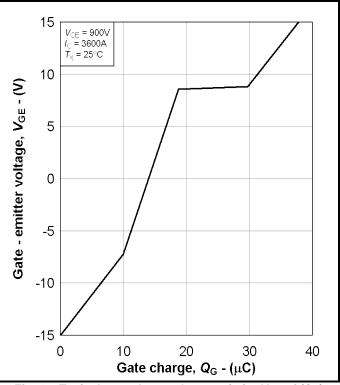


Fig. 16 Typical gate charge characteristic,  $V_{GE} = f(Q_G)$ 

## **PACKAGE DETAILS**

For further package information, please visit our website or contact Customer Services. All dimensions in mm, unless stated otherwise.

## DO NOT SCALE.

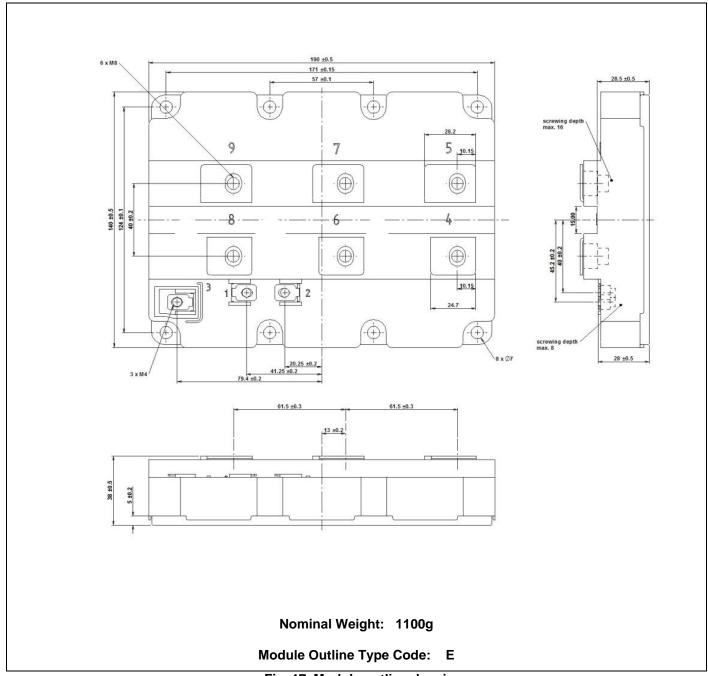


Fig. 17 Module outline drawing

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Extended exposure to conditions outside the product ratings may affect reliability leading to premature product failure. Use outside the product ratings is likely to cause permanent damage to the product. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture, a large current to flow or high voltage arcing, resulting in fire or explosion. Appropriate application design and safety precautions should always be followed to protect persons and property.

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